<u>1000V 15A</u>

\*G Denotes RoHS Compliant, Pb Free Terminal Finish.

# **ULTRAFAST SOFT RECOVERY RECTIFIER DIODE**

### **PRODUCT APPLICATIONS**

- Anti-Parallel Diode

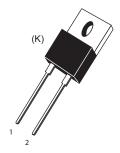
   Switchmode Power Supply
   Inverters
- Free Wheeling Diode -Motor Controllers
  - -Motor Controlle -Converters
  - -Inverters
- · Snubber Diode
- PFC

### **PRODUCT FEATURES**

- Ultrafast Recovery Times
- Soft Recovery Characteristics
- Popular TO-220 Package
- · Low Forward Voltage
- Low Leakage Current

#### **PRODUCT BENEFITS**

- Low Losses
- Low Noise Switching
- Cooler Operation
- · Higher Reliability Systems
- Increased System Power Density





- 1 Cathode
- 2 Anode Back of Case - Cathode

# **MAXIMUM RATINGS**

All Ratings:  $T_C = 25$ °C unless otherwise specified.

Symbol	Characteristic / Test Conditions	APT15D100K(G)	UNIT
V <sub>R</sub>	Maximum D.C. Reverse Voltage		
V <sub>RRM</sub>	Maximum Peak Repetitive Reverse Voltage	1000	Volts
V <sub>RWM</sub>	Maximum Working Peak Reverse Voltage		
I <sub>F(AV)</sub>	Maximum Average Forward Current (T <sub>C</sub> = 130°C, Duty Cycle = 0.5)	15	
I <sub>F(RMS)</sub>	RMS Forward Current (Square wave, 50% duty)	31	Amps
I <sub>FSM</sub>	Non-Repetitive Forward Surge Current (T <sub>J</sub> = 45°C, 8.3ms)	80	
T <sub>J</sub> ,T <sub>STG</sub>	Operating and StorageTemperature Range	-55 to 175	°C
T <sub>L</sub>	Lead Temperature for 10 Sec.	300	

### STATIC ELECTRICAL CHARACTERISTICS

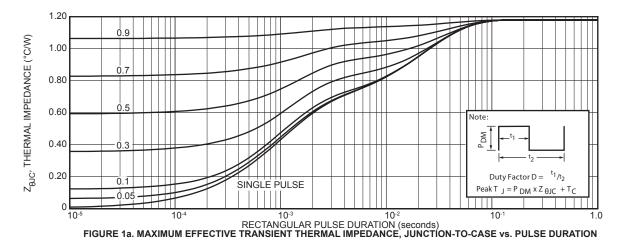
Symbol	Characteristic / Test Conditions		MIN	TYP	MAX	UNIT
V <sub>F</sub>	Forward Voltage	I <sub>F</sub> = 15A		1.9	2.3	Volts
		I <sub>F</sub> = 30A		2.2		
		I <sub>F</sub> = 15A, T <sub>J</sub> = 125°C		1.7		
I <sub>RM</sub>	Maximum Reverse Leakage Current	V <sub>R</sub> = V <sub>R</sub> Rated			250	μA
		$V_R = V_R$ Rated, $T_J = 125$ °C			500	
C <sub>T</sub>	Junction Capacitance, V <sub>R</sub> = 200V			17		pF

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
t <sub>rr</sub>	Reverse Recovery Time $I_F = 1A$ , $di_F/dt =$	$-100A/\mu s$ , $V_R = 30V$ , $T_J = 25^{\circ}C$	-	28		ne
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 15A$ , $di_F/dt = -200A/\mu s$ $V_R = 667V$ , $T_C = 25^{\circ}C$	-	260		ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	540		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	4	-	Amps
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 15A$ , $di_F/dt = -200A/\mu s$ $V_R = 667V$ , $T_C = 125°C$	-	300		ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	1550		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	9	-	Amps
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 15A$ , $di_F/dt = -1000A/\mu s$ $V_R = 667V$ , $T_C = 125°C$	-	150		ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	2150		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	26		Amps

# THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-Case Thermal Resistance			1.18	°C/W
$R_{\theta JA}$	Junction-to-Ambient Thermal Resistance			80	
W <sub>T</sub>	Package Weight		0.07		OZ
			1.9		g
Torque	Maximum Mounting Torque			10	lb•in
				1.1	N•m

Microsemi Reserves the right to change, without notice, the specifications and information contained herein.

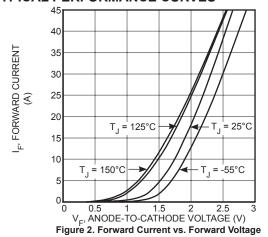


RC MODE L

Junction temp(°C)

Power (watts) 0.676 °C/W 0.00147 J/ °CCase temperatur e (°C)

#### **TYPICAL PERFORMANCE CURVES**



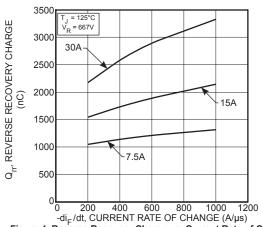
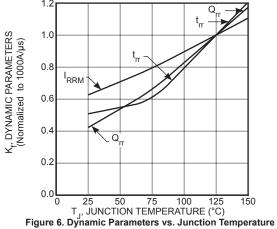
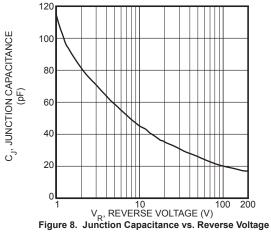


Figure 4. Reverse Recovery Charge vs. Current Rate of Change





# APT15D100K(G)

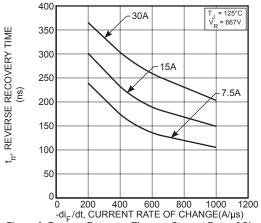


Figure 3. Reverse Recovery Time vs. Current Rate of Change

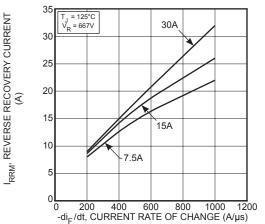


Figure 5. Reverse Recovery Current vs. Current Rate of Change

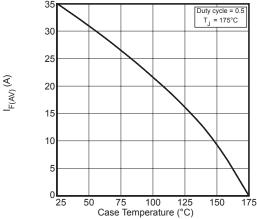


Figure 7. Maximum Average Forward Current vs. CaseTemperature

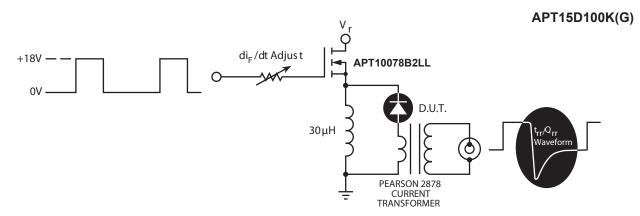


Figure 9. Diode Test Circuit

- 1 I<sub>F</sub> Forward Conduction Current
- di<sub>r</sub>/dt Rate of Diode Current Change Through Zero Crossing.
- 3 I<sub>RRM</sub> Maximum Reverse Recovery Current
- 4 t<sub>rr</sub> Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I<sub>RRM</sub> and 0.25, I<sub>RRM</sub> passes through zero.
- $\mathbf{5}$   $\mathbf{Q}_{rr}$  Area Under the Curve Defined by  $\mathbf{I}_{RRM}$  and  $\mathbf{t}_{RR}$ .

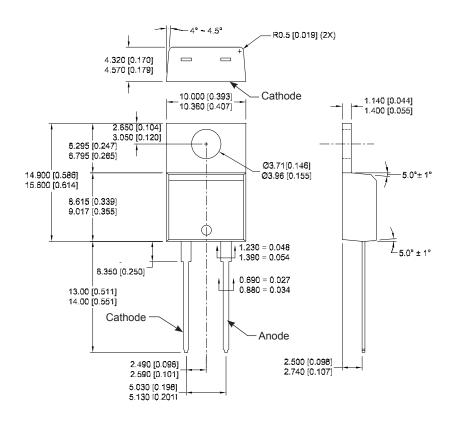
Zero

Sere

Sugh zero.

Figure 10. Diode Reverse Recovery Waveform Definition

#### TO-220 (K) Package Outline e3 100% Sn



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